

Final Assessment Test (FAT) – June 2022

Programme	B.Tech	Semester	Winter Semester 2021-22
Course Title	ELECTRONIC MATERIALS AND DEVICES	Course Code	BECE201L
Faculty Name	Prof. Sathya Sree J	Slot	F1+TF1
		Class Nbr	CH2021222300532
Time	3 Hours	Max. Marks	100

Answer all the questions

Part - A (10 X 10 Marks)

Answer **All** questions

1. (a) Explain skin effect with neat diagram. [10]_g
- (b) The hall effect of silicon specimen is $4.55 \times 10^{-4} \text{ m}^3 \text{C}^{-1}$ and its resistivity is $8.88 \times 10^{-3} \Omega \text{ m}$. Determine the carrier concentration and mobility. [10]_g
2. A new semiconductor has $N_c = 10^{19} \text{ cm}^{-3}$, $N_v = 5 \times 10^{18} \text{ cm}^{-3}$, and $E_g = 2 \text{ eV}$. If it is doped with 10^{17} donors (fully ionized), calculate the electron, hole, and intrinsic carrier concentrations at 627°C . Sketch the simplified band diagram, showing the position of E_F . [10]_g
3. Draw the energy band diagram of n-type and p-type semiconductor and explain how the Fermi level varies with temperature and doping concentration with an example. [10]_g
4. (i) The electron concentration in silicon is given by $n(x) = 10^{15} e^{-(x/L_n)} \text{ cm}^{-3}$ ($x \geq 0$) where $L_n = 10^{-4} \text{ cm}$. The electron diffusion coefficient is $D_n = 25 \text{ cm}^2/\text{s}$. Determine the electron diffusion current density at $x = 10^{-4} \text{ cm}$. [10]_g
- (ii) The required conductivity of a silicon material must be $\sigma = 1.5 (\Omega\text{-cm})^{-1}$. If $\mu_n = 1000 \text{ cm}^2/\text{V-s}$ and $\mu_p = 375 \text{ cm}^2/\text{V-s}$, Find the electron concentration.
5. Explain the principle of operation of tunnel diode with energy band diagram. [10]_g
6. A PN silicon device is fabricated with a phosphorus donor concentration of $5 \times 10^{15} \text{ cm}^{-3}$. The sample is bombarded with boron acceptors to create a P-type material of $1 \times 10^{17} \text{ cm}^{-3}$ concentration and a cross sectional area of $1 \times 10^{-2} \text{ cm}^2$. Assume complete ionization $KT/q = 26 \text{ mV}$ and intrinsic carrier concentration $n_i = 1.5 \times 10^{10} \text{ cm}^{-3}$ at operating temperature $T = 300 \text{ K}$. Calculate: [10]_g
- (i) The built-in potential at the PN junction.
- (ii) Total depletion width.
- (iii) Maximum electric field at the junction.
7. Explain the input and output characteristics of Common Emitter (CE) configuration of NPN transistor and draw the corresponding small-signal equivalent model. [10]
8. Explain the C-V characteristics of a MOS capacitor with a p-type substrate with the help of energy band diagram. [10]
9. If the drain of an n-channel MOSFET is shorted to the gate with a threshold voltage (V_T) of MOSFET as 0.5 V . Identify the region of operation. Also, If the drain current (I_D) is specified as 2 mA for $V_{GS} = 3 \text{ V}$, then estimate the drain current and transconductance using the appropriate formula for $V_{GS} = 5 \text{ V}$. [10]
10. Suggest a suitable material that has high electrical and thermal conductivity for a semiconductor device along with its working principle and necessity. [10]_g

